



PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application No.: 10/791,629

Filing Date: March 03, 2004

Applicant: Soo-Chan Lee

Group Art Unit: 2829

Examiner: Jermele M. Hollington

Title: SYSTEM AND METHOD FOR TESTING SEMICONDUCTOR
DEVICES

Attorney Docket: 2421-000033/US

Customer Service Window
Randolph Building
401 Dulany Street
Alexandria, VA 22314
Mail Stop Amendment AF

December 4, 2006

AMENDMENT AFTER FINAL

Sir:

In response to the Final Office Action mailed October 3, 2006, the following remarks are respectfully submitted in connection with the above-identified application.

Listing of the Claims begin on page 2 of this Amendment.

Remarks begin on page 15 of this Amendment.

Please enter AF

	Claims remaining after Amendment		Highest number previously paid for		Present extra
Total	40	-	42	=	0
Independent	13	-	13	=	0